

NASA TECH BRIEF

Marshall Space Flight Center



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Radiographic Inspection Specifications for Electronic Components

Preliminary test specifications for the radiographic inspection of electronic devices such as integrated circuits, discrete components, relays and coils, outline requirements, test conditions, and recommended techniques for such operations. Detailed quality assurance provisions cover the areas of personnel training, radiographic equipment, radiographic test procedures, and inspection and examination of radiographs. Supplementary information includes the accept/reject criteria for the radiographic inspection of resistors, capacitors, transistors, hybrid microcircuits, diodes, small coils and transformers. Although these test specifications are not official, they should be useful in establishing in-house radiographic test procedures for those involved in the manufacture or use of electronic circuits and components.

Note:

Requests for further information may be directed to:

Technology Utilization Officer
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Huntsville, Alabama 35812
Reference: B71-10438

Patent status:

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